



VACUUM X-RAY FLUORESCENCE ANALYSIS (VACUUM XRF)

Precisely Analyzing Layers and Materials

When accuracy matters. Vacuum XRF offers a powerful solution for the nondestructive examination of materials and coatings. Vacuum operation allows for significantly better detection of low-energy fluorescence signals. As a result, light elements in particular—such as phosphorus, sulfur, silicon, and aluminum—can be analyzed with much greater precision.

Get advice now. We'll help you choose the right measurement strategy for your samples.

- Non-destructive measurement
- Results within minutes
- No sample preparation required
- Measurement of film thickness
- Improved detection limits
- Highest measurement accuracy
- Determination of phosphorus content in chemical nickel
- Analysis of very thin films (CIGS, CIS, CdTe)



YOUR CONTACT PERSON
Alexander Krieger
krieger@fem-institute.com
+49 7171 1006-316